

*Search for supersymmetry in events with photons and missing  
transverse energy*

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on behalf of *CMS* collaboration

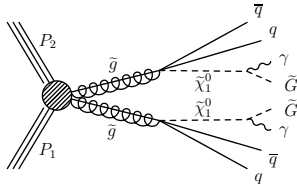
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## Analysis Overview

Search for General gauged mediated (GGM) supersymmetry breaking in **final state involving photons**. The data sample corresponds to an integrated luminosity of  $2.32 \text{ fb}^{-1}$  of proton proton collisions at  $\sqrt{s} = 13 \text{ TeV}$  was collected with the CMS detector at the LHC in 2015.

GGM supersymmetry breaking can produce events with **double photons, jets and significant missing energy ( $E_T^{miss}$ )**.



We assume gluino pair production where the NLSP neutralino decays to a gravitino and photon ( $\tilde{\chi}_1^0 \rightarrow \tilde{G}\gamma$ ), resulting in characteristic events with jets, two photons and large  $E_T^{miss}$

## Backgrounds

### Quantum Chromodynamics (QCD) background

- Most significant background due to huge QCD cross section
- Can have real photons in the final state or we can get electromagnetically-rich jet fragmentation mimicking the response of a photon
- $E_T^{miss}$  comes from mis-measured hadronic activity.

### Electroweak (EWK) background

- Includes  $W\gamma$  and  $W + jet$  events
  - $W \rightarrow e\nu$  and the electron is misidentified as a photon
  - $W + jet$  events, one of the jets fakes a photon
- Genuine  $E_T^{miss}$  from the neutrino

### Other backgrounds-small and studied with Monte Carlo (MC).

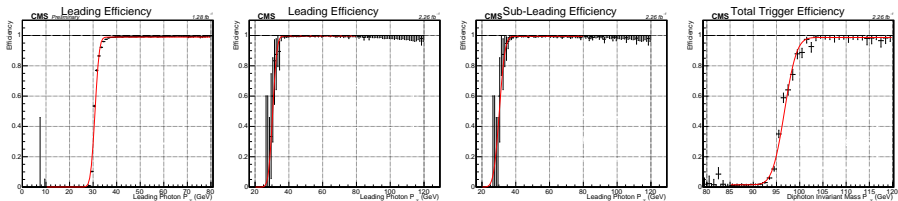
- $Z\gamma\gamma \rightarrow \nu\nu\gamma\gamma$
- $W\gamma\gamma \rightarrow l\nu\gamma\gamma$
- $t\bar{t}\gamma\gamma$

# Trigger

Primary analysis trigger:

*HLT\_Diphoton30\_18\_R9Id\_OR\_IsoCalId\_AND\_HE\_R9Id\_Mass95*

- Lead Photon  $P_T > 30\text{GeV}$  and trail for photon  $P_T > 18\text{GeV}$
- $M_{\gamma\gamma} > 95\text{GeV}$



HLT efficiency is calculated by a tag and probe method and is 98.6% for photon  $P_T > 40\text{GeV}$

Trigger requires two photons passing the sub-leading filter and one photon passing the leading filter, so that the total efficiency  $\epsilon_{tot} = \epsilon_{lead,lead} \times \epsilon_{lead,sub} \times \epsilon_{sub,sub}$

## Object Selection

### Muons

- $P_T > 30\text{GeV}$
- $|\eta| < 1.4442$
- Passes medium muon ID
- Passes loose muon isolation

### Electrons

- From PF photon collection
- $P_T > 40\text{GeV}$
- $|\eta| < 1.4442$
- Passes medium photon ID
- Fails pixel seed veto
- Remove electrons that overlap within  $\Delta R < 0.4$  of a muon

### Photons

- From PF photon Collection
- $P_T > 40\text{GeV}$
- $|\eta| < 1.4442$
- Passes medium photon ID
- Passes Pixel seed veto

### Jets

- $P_T > 30\text{GeV}$
- $|\eta| < 2.4$
- Passes PF Loose ID
- Remove jets that overlap within  $\Delta R < 0.4$  of a muon, electron, or a photon

## Fake Selection

'Fake Photons' are photons that fail isolation or shape requirements.

Primarily composed of **electromagnetically rich jets reconstructed as photons**

- Control Sample with fakes are used to model the QCD background
- Make Fakes orthogonal to Photons by inverting charged hadron isolation or  $\sigma_{i\eta i\eta}$  requirements of the medium photon ID.  
(  $1.33\text{GeV} < \text{charged hadron isolation} < 15\text{GeV}$  XOR  $0.0102 < \sigma_{i\eta i\eta} < 0.0150$  )

Events are sorted into **four categories** depending on the selection of their **highest- $p_T$  electromagnetic objects**:

- $\gamma\gamma$
- $ee$
- $ff$
- $e\gamma$

## Control and Candidate Sample

### Double electron Sample (ee)

- Used to model EM objects in the QCD background
- Require  $75\text{GeV} < m_{ee} < 105\text{GeV}$  to collect  $Z \rightarrow ee$  events
- Require  $\Delta R > 0.3$  between electrons

### Double fake sample (ff)

- Passes the primary trigger
- Used to model EM objects in the QCD background
- require  $m_{ff} > 105\text{GeV}$
- require  $\Delta R > 0.3$  between fakes.

### Candidate DiPhoton Sample ( $\gamma\gamma$ )

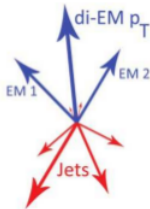
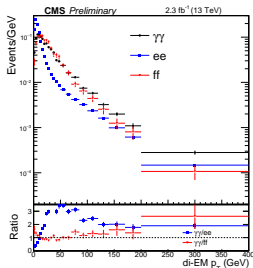
- passes primary trigger
- Require  $m_{\gamma\gamma} > 105\text{GeV}$
- $\Delta R > 0.3$  between photons

Signal Region is  $E_T^{miss} > 100\text{GeV}$

# QCD Background Estimation - Backgrounds without true $E_T^{miss}$

## Strategy

- Processes that lack from genuine  $E_T^{miss}$ , but can emulate GGM signal topologies if the hadronic activities in the event are poorly measured.
- Used **double electrons** and **double fakes** control samples to estimate the  $E_T^{miss}$  distribution of QCD backgrounds.
- But this samples have different amounts of hadronic activity than the candidate  $\gamma\gamma$  sample.

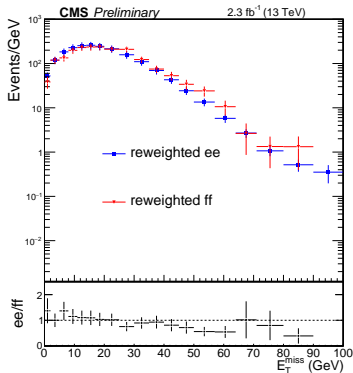
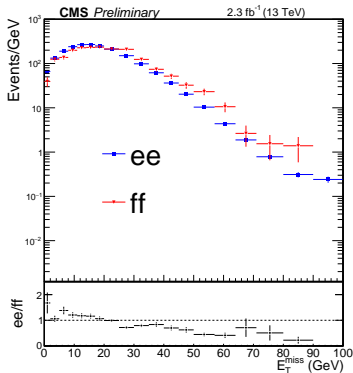


- Model the hadronic recoil of the event with the di-EM  $p_T$  of the event**, where di-EM  $p_T$  is the vector sum of the  $P_T$  of the two electromagnetic object.
- Reweight the control samples to correct for the differences in hadronic activity.**



Reweight  $E_T^{miss}$  backgrounds

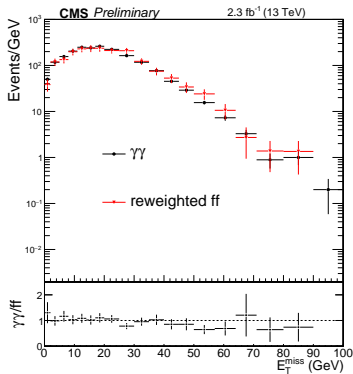
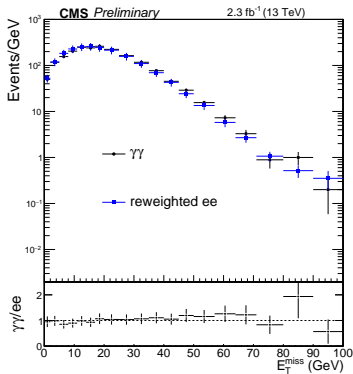
Unweighted (left) and di-EM  $p_T$  reweighted (right)  $E_T^{miss}$  distributions of the ee and ff samples



Samples are normalized to  $E_T^{miss} < 50$  GeV of the  $\gamma\gamma$  (signal contamination < 1% )

## Comparison to Candidate $\gamma\gamma$ Sample

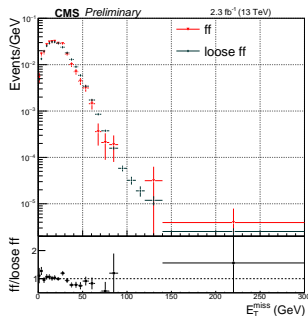
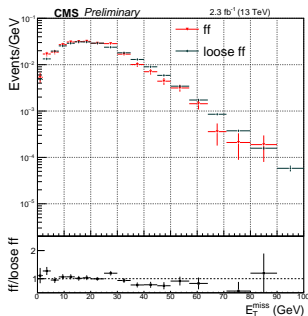
Comparing the candidate  $E_T^{miss}$  distribution to the distributions for the ee (left) and ff (right) control samples.



Samples are normalized to  $E_T^{miss} < 50$  GeV of the  $\gamma\gamma$

## Estimation of pure QCD background

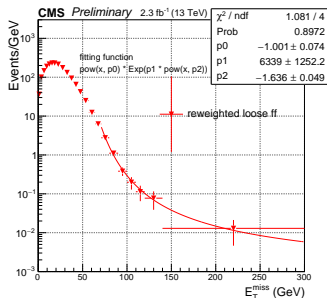
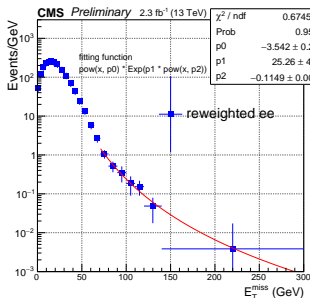
- The primary background estimate comes from the **double electron sample**.
- We use the prediction from double fake as a **systematic uncertainty** on the estimate from the ee sample.
- Low statistics from ff sample in  $E_T^{miss} > 100$  GeV signal region.



- Tight fake and loose fake samples match well in  $E_T^{miss} < 100$  GeV region.
- Loose fake samples can be used to model the shape in high  $E_T^{miss}$  region.
- Determine ff sample in signal region from looser fake definition.

## Systematic Uncertainty from Shape Difference

- Fit reweighted ee and loose ff samples for  $70 \text{ GeV} < E_T^{\text{miss}} < 300 \text{ GeV}$  with a function  $\chi^{p0} \exp(p1\chi^{p2})$  with fit parameters p0, p1, p2
- Integrate fits in each  $E_T^{\text{miss}}$  bin for  $E_T^{\text{miss}} > 100 \text{ GeV}$ .
- Difference between ee and loose ff result gives shape uncertainties in that bin.
- Largest uncertainty in the last bin due to the large bin width.



## Final QCD Estimate

$E_T^{miss}$ (GeV)	Bkg Prediction
100-110	$1.85 \pm 0.96$
110-120	$1.53 \pm 0.63$
120-140	$0.97 \pm 0.62$
> 140	$0.61 \pm 2.15$

- Di-EM  $p_T$  reweighting uncertainty comes from propagating toy Di-EM  $p_T$  plots to the reweighted  $E_T^{miss}$  distribution.
- Additional systematic comes from the differences between reweighting with the di-EM  $p_T$  only and reweighting with di-EM  $p_T$  and jet multiplicity.

$E_T^{miss}$ (GeV)	Systematic Uncertainty	Value (%)
100-110	Di-EM $p_T$ reweighting	15.11
	Jet multiplicity reweighting	33.77
	Shape difference between ee and ff	18.18
	Statistical uncertainty of ee sample	30.81
110-120	Di-EM $p_T$ reweighting	16.60
	Jet multiplicity reweighting	14.87
	Shape difference between ee and ff	12.07
	Statistical uncertainty of ee sample	33.33
120-140	Di-EM $p_T$ reweighting	33.31
	Jet multiplicity reweighting	29.39
	Shape difference between ee and ff	14.40
	Statistical uncertainty of ee sample	41.75
> 140	Di-EM $p_T$ reweighting	39.75
	Jet multiplicity reweighting	20.34
	Shape difference between ee and ff	150.36
	Statistical uncertainty of ee sample	70.98

EWK background in the signal region ( $E_T^{miss} > 100\text{GeV}$ ) comes mainly from  $W\gamma \rightarrow e\nu\gamma$  where the electron is misidentified as a photon.

- Calculate the ratio of the electrons faking photons,  $f_{e \rightarrow \gamma}$  using the  $Z \rightarrow ee$  invariant mass peak in both an ee sample and an  $e\gamma$  sample.
- To get the final EWK background estimate, we weight the  $e\gamma E_T^{miss}$  distribution by  $f_{e \rightarrow \gamma} / (1 - f_{e \rightarrow \gamma})$  to get the number of  $e\gamma$  events that sneak into the candidate  $\gamma\gamma$  sample.

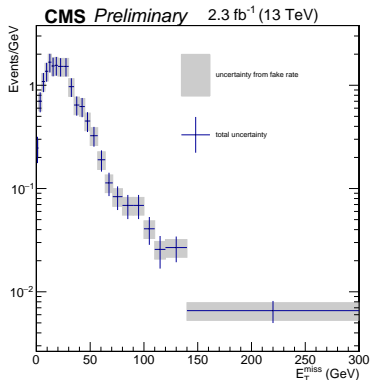
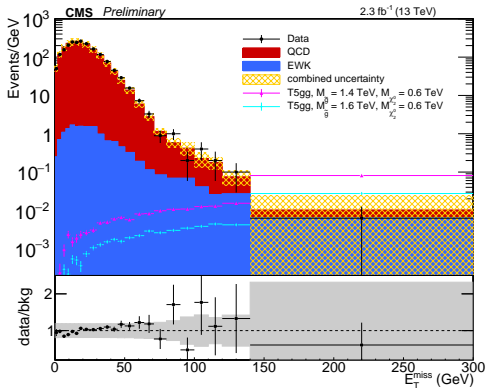


Table: Estimation of total EWK background for  $E_T^{miss} > 100\text{ GeV}$

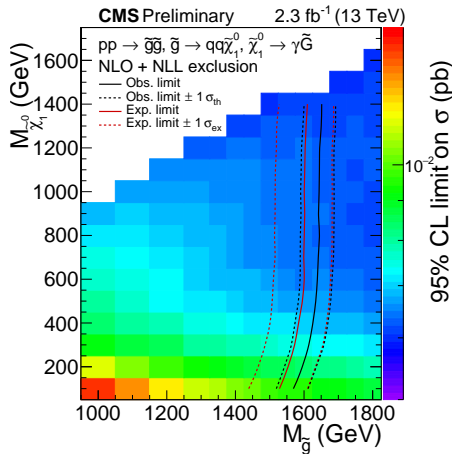
$E_T^{miss}$ bin (GeV)	Expected
100 – 110	$0.11 \pm 0.09$
110 – 120	$0.07 \pm 0.06$
120 – 140	$0.14 \pm 0.11$
140 – <i>Inf</i>	$0.27 \pm 0.22$

## Observed vs Expected

$E_T^{miss}$ (GeV)	Expected	Observed
100-110	$2.26 \pm 0.96$	4
110-120	$1.79 \pm 0.64$	2
120-140	$1.51 \pm 0.64$	2
> 140	$1.64 \pm 2.16$	1



## Limits



- An expected exclusion reach for the analysis was done using the modified frequentist CLs methods
- This is based on long-likelihood test statistic that compares the likelihood of the SM-only hypothesis to the likelihood of the presence of signal in addition to the SM conditions
- The likelihood functions are based on the expected shape of the  $E_T^{miss}$  distribution for signal and background in four separate bins.
- For typical values of neutralino mass, we expect to exclude gluino masses out of 1.5 TeV, improving the reach of previous searches performed at center-of-mass energies of 8 TeV.



## Conclusions

- Full analysis has been done on 13 TeV data
- Even with  $2.3fb^{-1}$  of data, we are able to extend our reach from 8TeV analysis
- No evidence of SUSY seen, but we expect to probe even higher mass scales this year with a larger dataset.

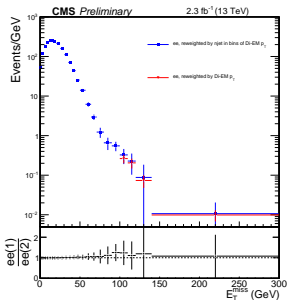
# Back Up

## Jet multiplicity Reweighting

The difference in jet multiplicity between the candidate sample and the control sample can also affect the overall  $E_T^{miss}$  resolution of the background estimation .

The jet multiplicity distribution for the candidate and the ff samples are similar, but the candidate and ee are different.

To investigate the effect of jet multiplicity reweighting, we plotted the  $eeE_T^{miss}$  distribution reweighting by the jet multiplicity in bins of di-EM  $p_T$ .



The difference between them is small.

Choose not to reweight by the jet multiplicity, but we take the difference as a systematic uncertainty.

## Contributions to control samples

There is a small Contribution to the ee control sample from  $t\bar{t}$  events and the contribution to the ff sample from  $Z \rightarrow \nu\bar{\nu}$

$t\bar{t}$  events will contribute  $17.27 \pm 0.98$ . and  $Z \rightarrow \nu\bar{\nu}$  contribution is almost negligible.  
To get rid of the contamination we subtract the shape of  $t\bar{t}$  from our ee control sample.